



# **Anisotropy and interlayer interaction in Mo/Si multilayers**

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## **Abstract**

The interlayer interaction in superconducting Mo/Si multilayers is determined by the measurements of the upper critical magnetic field and the magnetoconductivity in magnetic fields, parallel and perpendicular to the layers. From these measurements we determined the anisotropy parameter,  $\gamma$ , and the effective thickness,  $L_{\text{eff}}$ , which characterize the mutual electronic interaction between the Mo layers across the Si layer. Both quantities oscillate in dependence of the Mo layer thickness for Mo/Si series with constant Si layer thickness.